



PATENT 28

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Shing M. Lee

Attorney Docket No.: KLA1P012/P647US

Application No.: 09/695,726

Examiner: Fernandez, K.

Filed: October 23, 2000

Group: 2881

Title: FILM THICKNESS MEASUREMENT
USING ELECTRON-BEAM INDUCED
X-RAY MICROANALYSIS

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail to: Commissioner for Patents, Washington, DC 20231 on March 25, 2003.

Signed: 

Tara Hayden

AMENDMENT TRANSMITTAL

Commissioner for Patents
Washington, DC 20231

Sir:


Transmitted herewith is an Amendment in the above-identified application.

The fee has been calculated as shown below.

	Claims After Amendment		Highest Previously Paid For	Present Extra	Small Entity Rate Fee	Large Entity Rate Fee
Total Claims	25	MINUS	30	00	x 9 =	x 25 =
Independent Claims	04	MINUS	06	00	x 42 =	x 84 =
Multiple Dependent Claim Present and Fee Not Previously Paid					\$140.00	\$280.00
Total					\$	\$

- ☐ Applicant(s) hereby petition for a ____ month extension(s) of time to respond to the aforementioned Office Action.
- ☒ Applicant(s) believe that no (additional) Extension of Time is required; however, if it is determined that such an extension is required, Applicant(s) hereby petition that such an extension be granted and authorize the Commissioner to charge the required fees for an Extension of Time under 37 CFR 1.136 to Deposit Account No. 500388.
- ☐ Enclosed is our Check No. ____ in the amount of \$ ____ to cover the additional claim fee and/or extension of time fees.
- ☒ Please charge the required fees, or any additional fees required to facilitate filing the enclosed response, to Deposit Account No. 500388 (Order No. KLA1P012).

Respectfully submitted,
BEYER WEAVER & THOMAS, LLP


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PATENT

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Attorney Docket No.: #14/13
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to: Assistant Commissioner for Patents, Washington, DC 20231 on March 25, 2003.

Printed Name: Tara Hayden

Signed: 

RESPONSE C AFTER FINAL

Box AF

Assistant Commissioner for Patents
Washington, D.C. 20231

Dear Sir:

In response to the Office Action dated January 29, 2002, a response to which
is due April 29, 2003 please consider the following remarks:

IN THE CLAIMS:

Please **CANCEL** claim 15 without prejudice or disclaimer.

REMARKS

In the Office Action, the Examiner rejected claims 1, 4, and 31 under 35
U.S.C. § 103(a) as being unpatentable over U.S. Patent No. 4,962,516 to Soezima and
U.S. Reg. No. H589 issued to Sartore, claims 1, 4, 11, 16-17, 21-22, 24, 26-27, 29, 32,
and 24 under §103(a) as being unpatentable over Soezima and in view of U.S. Patent
No. 5,210,414 issued to Wallace et al., claims 6-7, 9, 18, 25, and 30 under §103(a) as
being unpatentable over Soezima, Wallace et al. and further in view of U.S. Patent